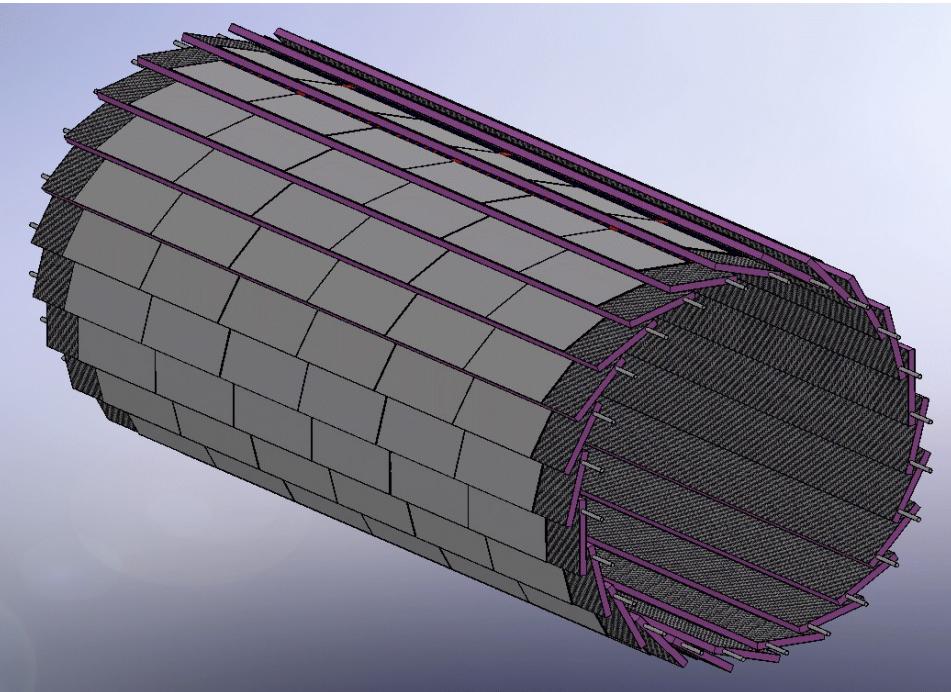


Intermediate Silicon Tracker status

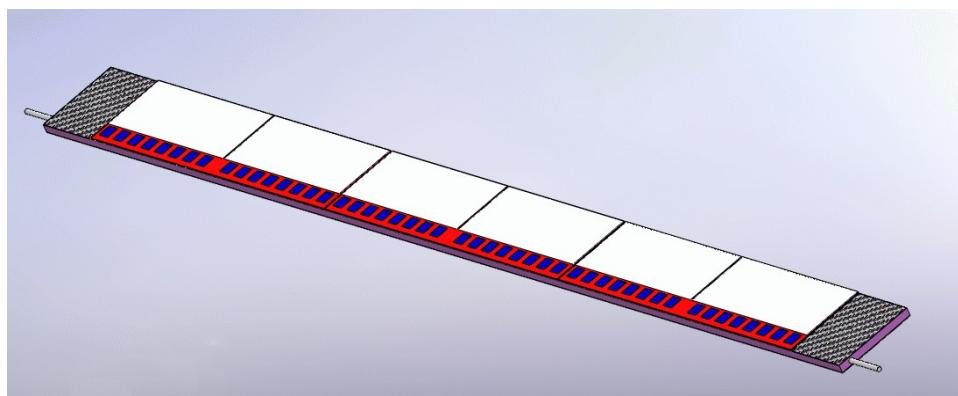
**Gerrit van Nieuwenhuizen
HFT monthly meeting
LBNL, May 14, 2009**



IST design (2008)

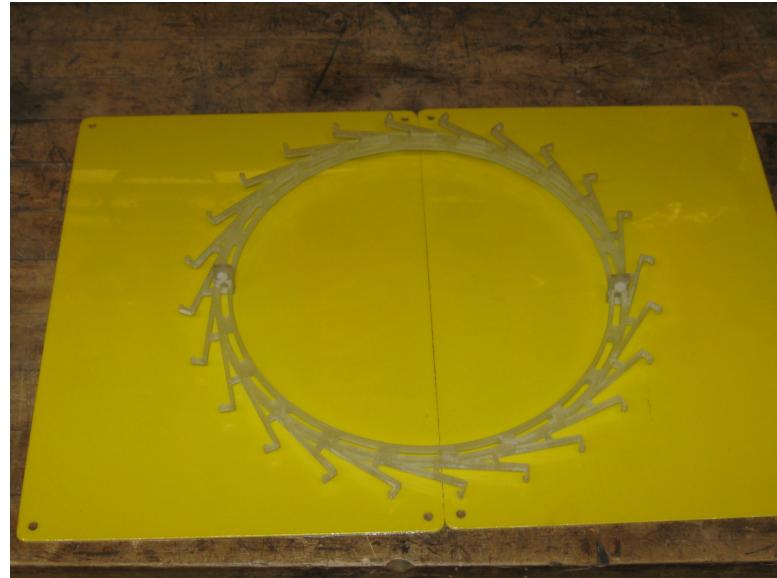
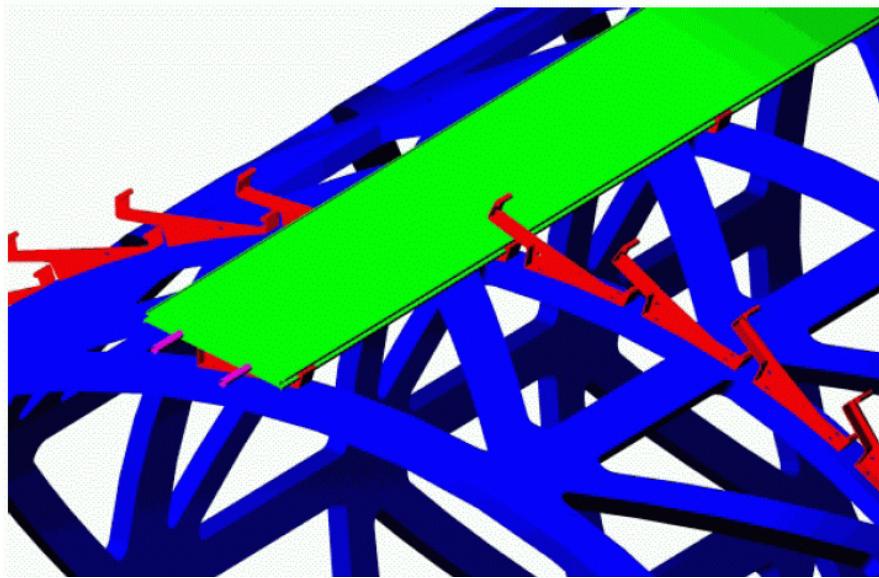


24 tiled ladders at 14cm radius

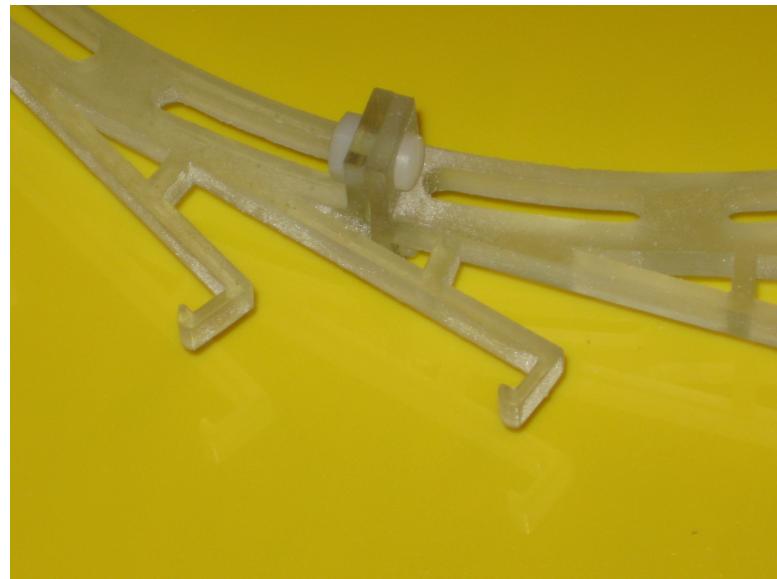


3 modules (= 6 sensors) per ladder

Ladder and support prototyping

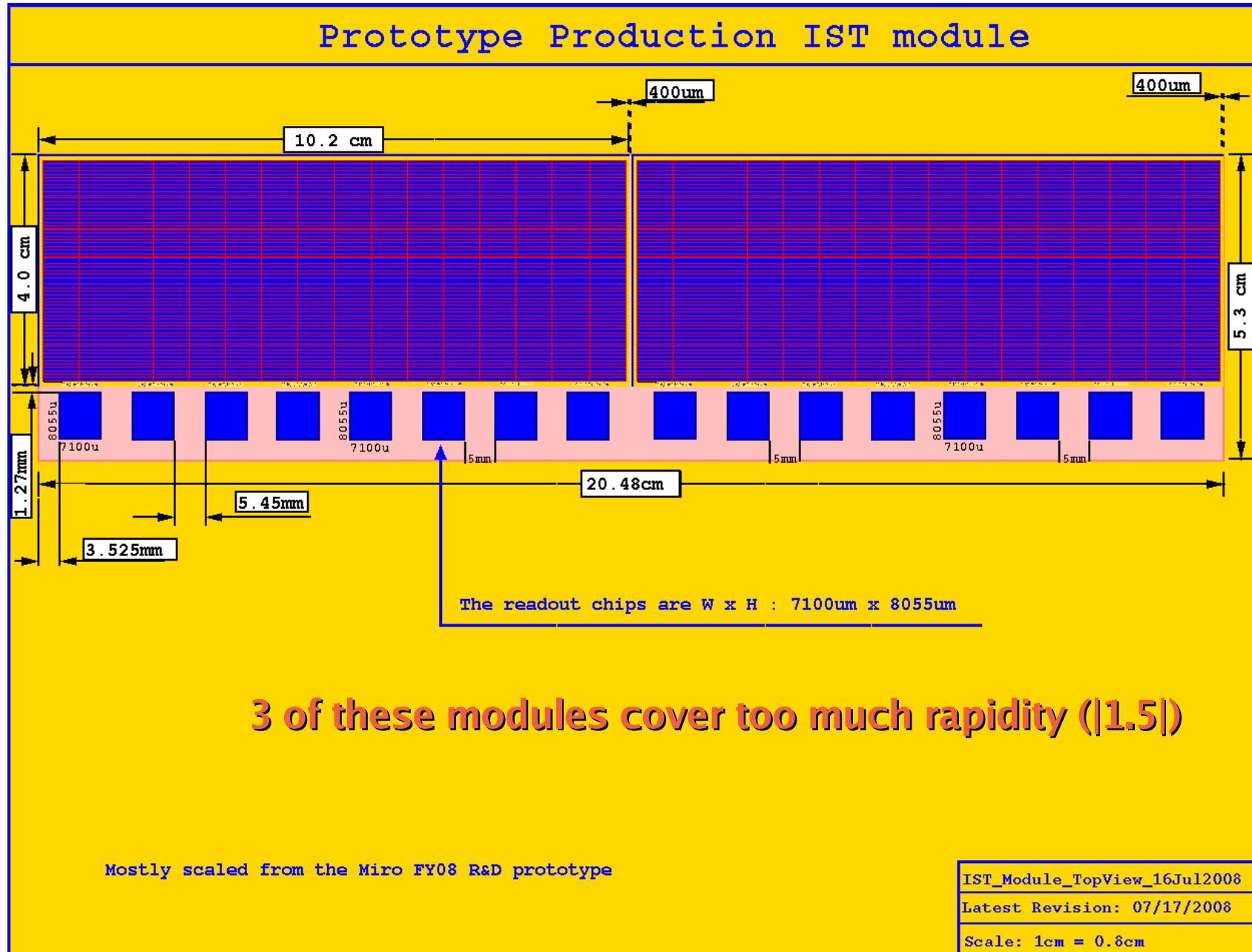


Ladder prototype



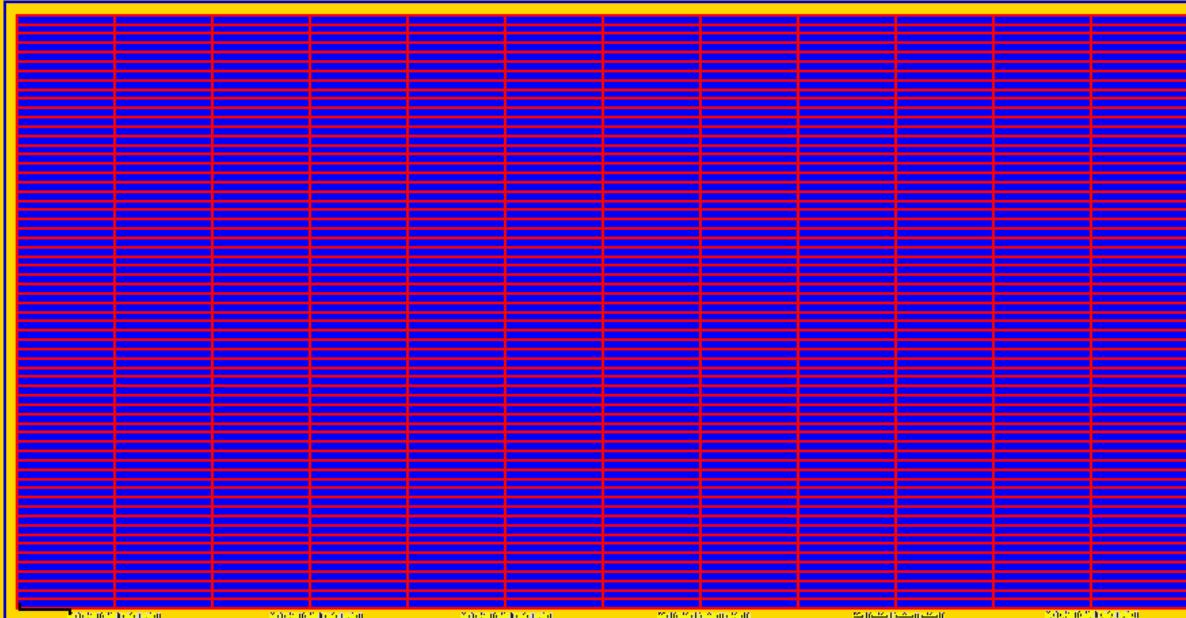
Support rapid prototyping

The 2008 module



A shorter sensor for 2009

IST silicon pad sensor design for Hamamatsu quote



Silicon sensor size: 76.900mm x 40.000mm

Active area pitch: 6275um x 596um

Edge structure left & right: 800um

Top edge structure: 800um

Bottom edge structure: 1056um

12 columns x 64 rows

6 Sensors cover a bit over 1.2 in rapidity

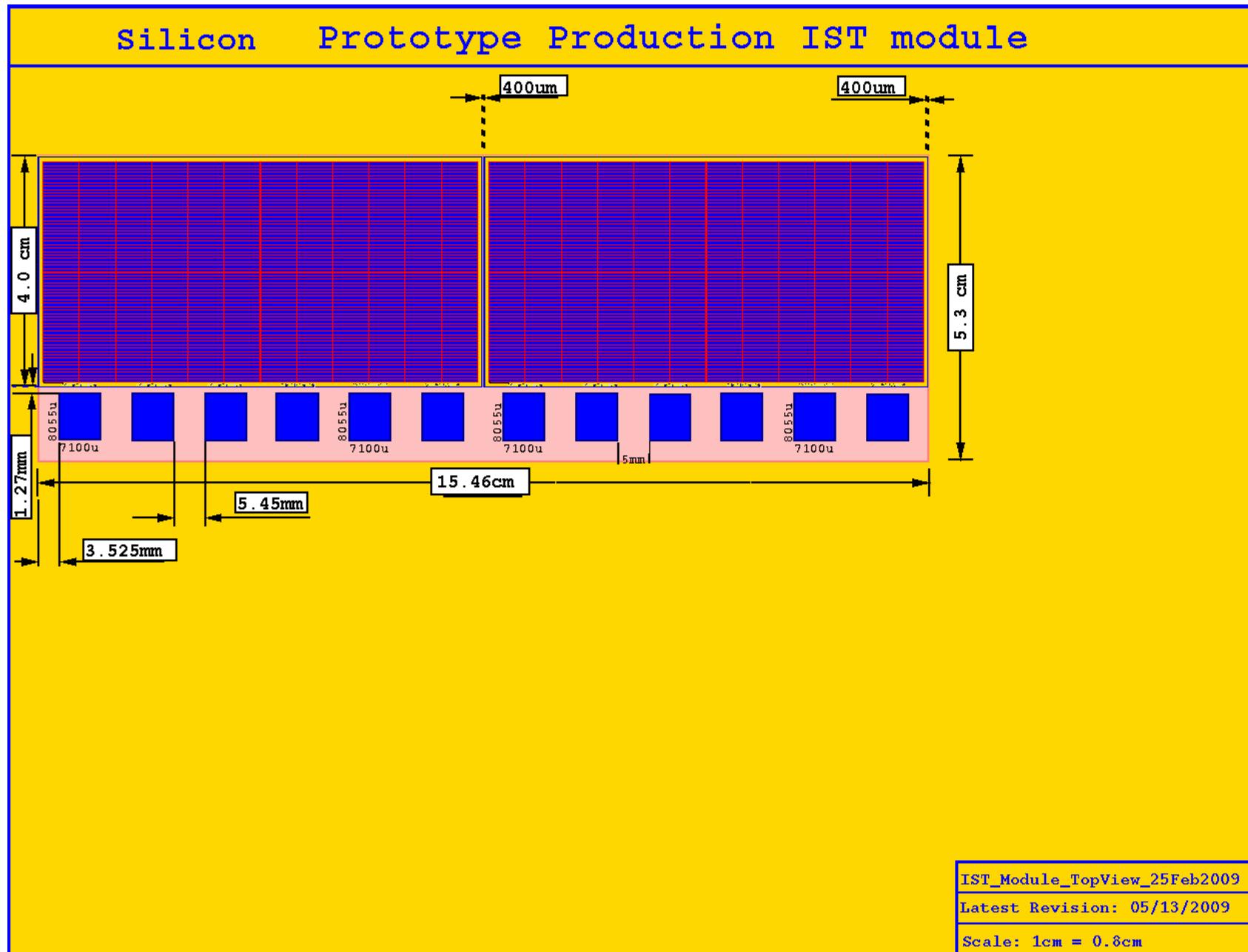
400um gaps (max) between sensors means total gap of 2000um between sensors
leading to a spatial efficiency of 97.8%

HamamatsuDesign_25Apr2009

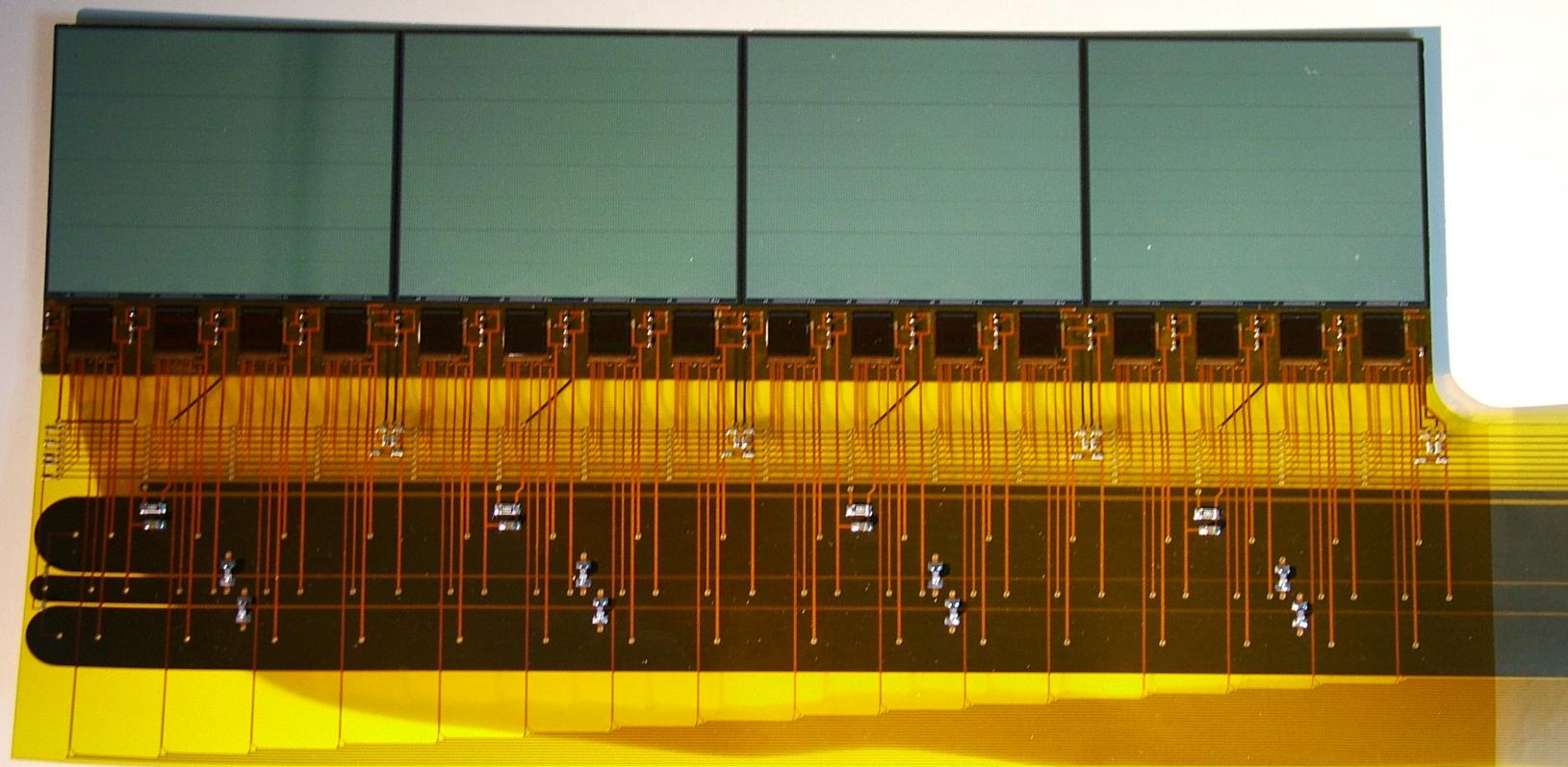
Latest Revision: 05/12/2009

Scale: 1cm = 0.4cm

Makes a shorter module

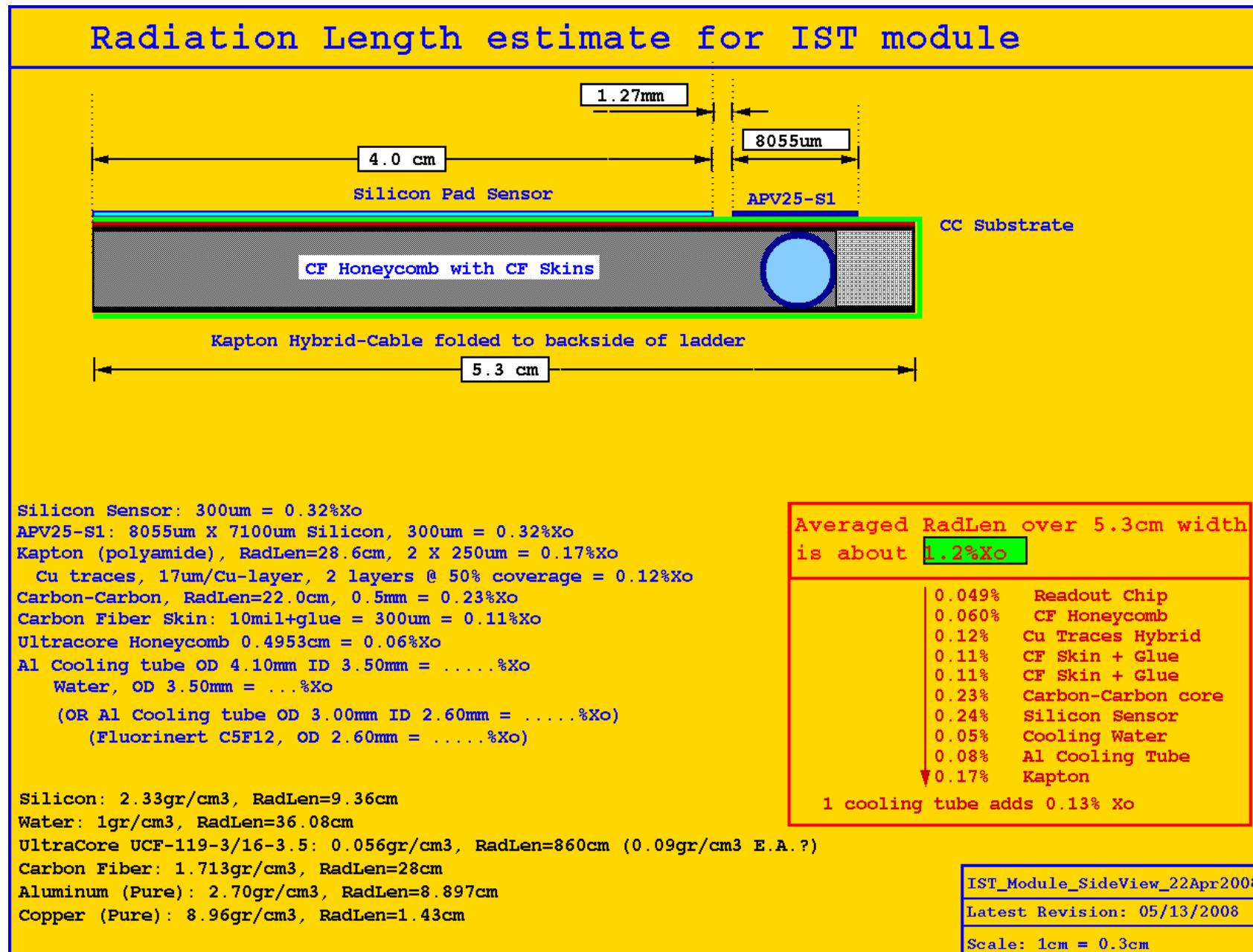


Prototype with 4 sensors

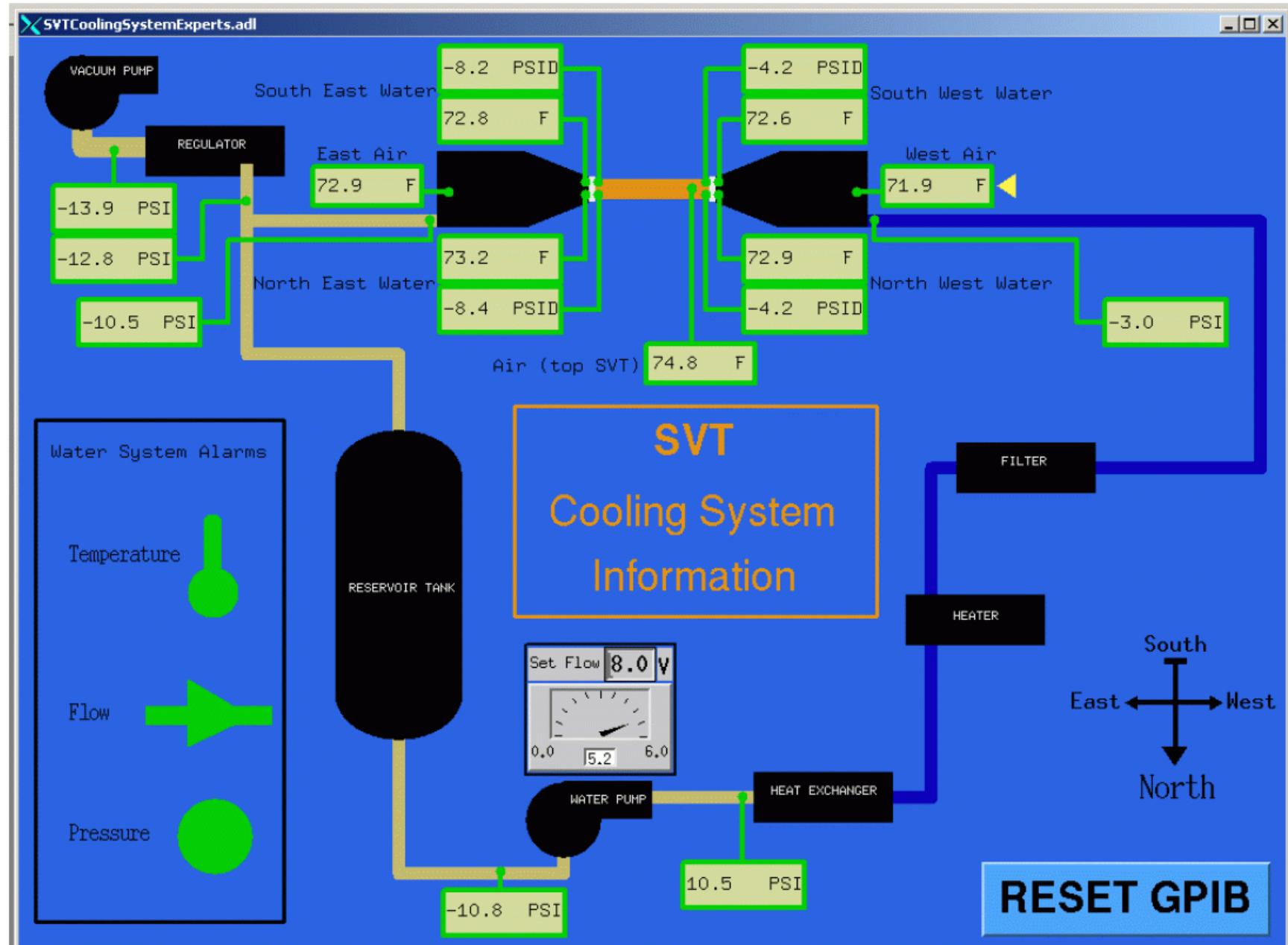


Setting up the wire bonding parameter

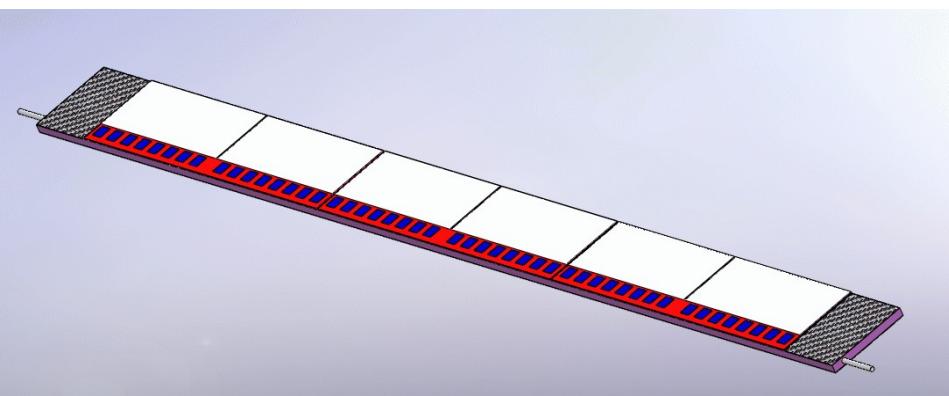
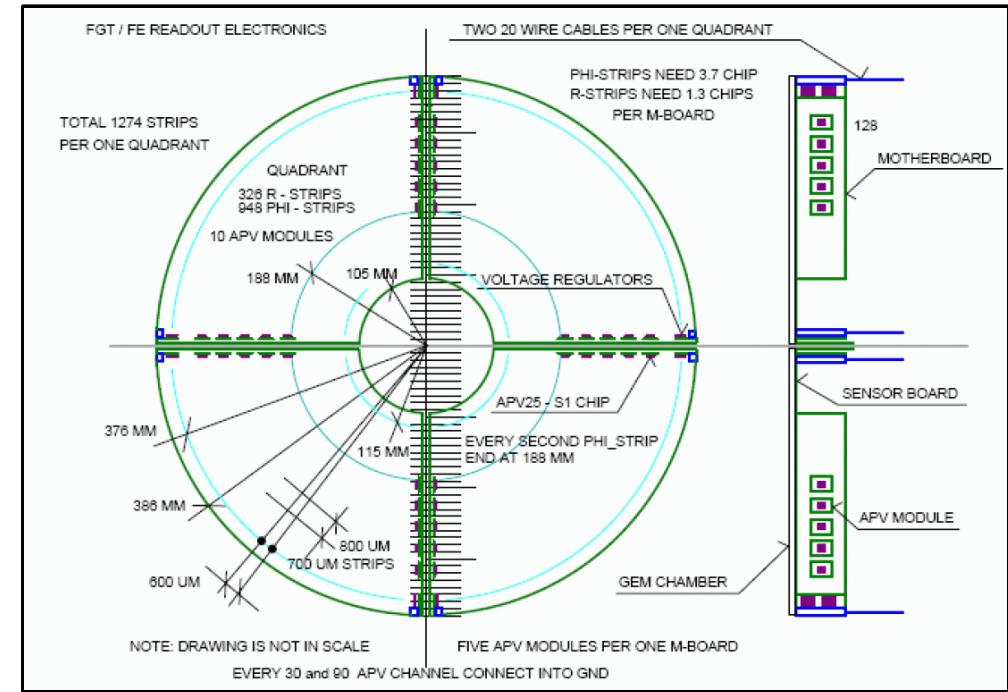
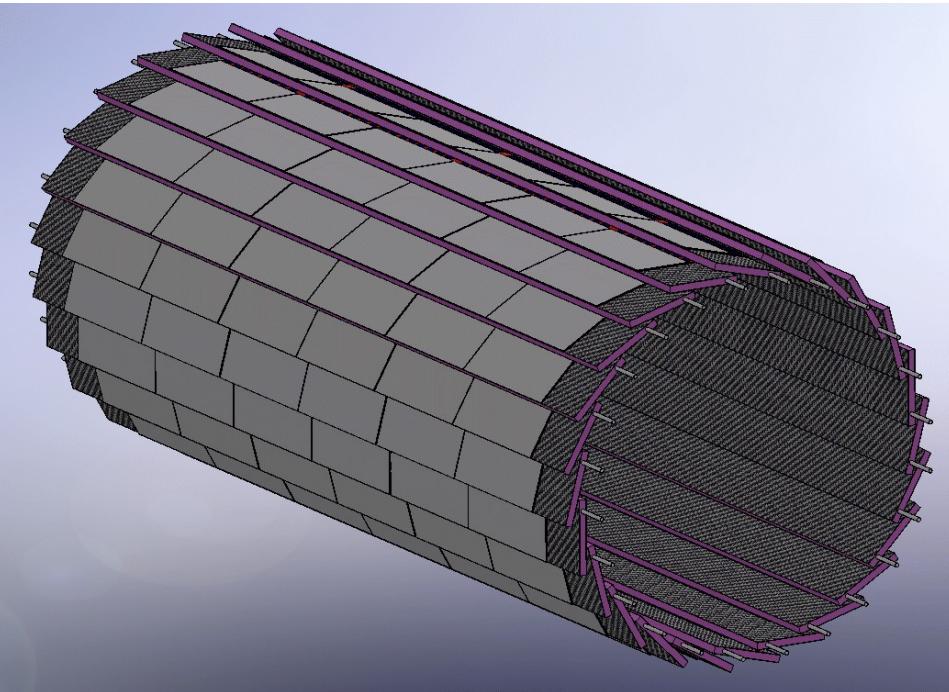
Optimizing material budget



Refurbish SVT cooling system



Number of chips needed

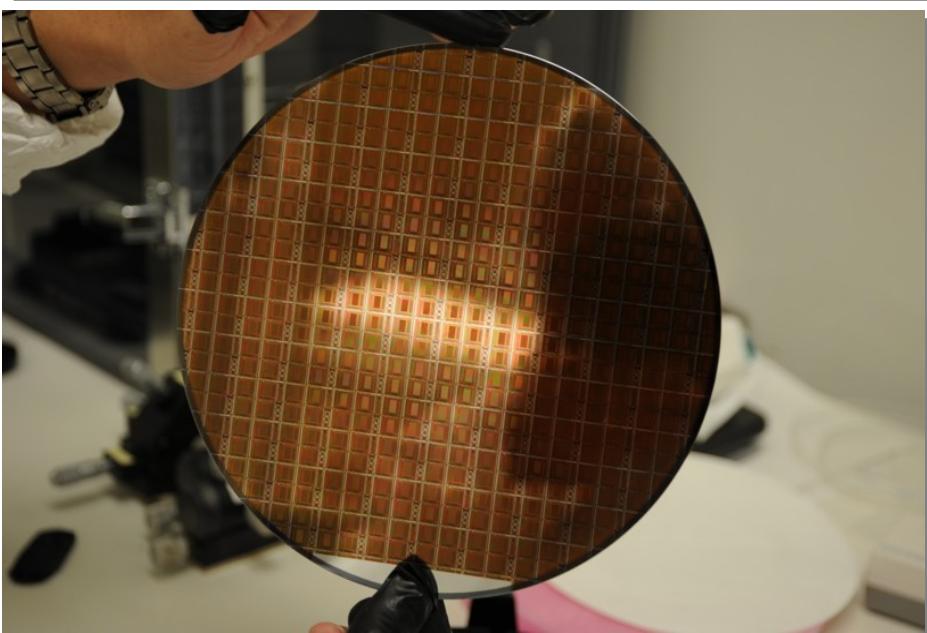


FGT: 600 chips (50% spares, 40% cont.)

IST: 1800 chips (10% spares, 40% cont.)

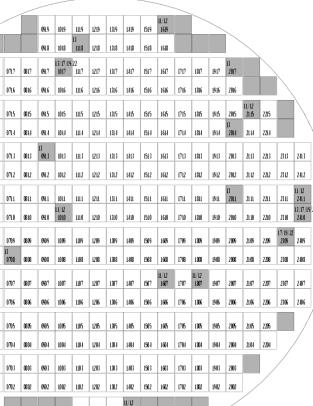
2400 APV25-S1 chips to procure

8 APV Wafers at MIT

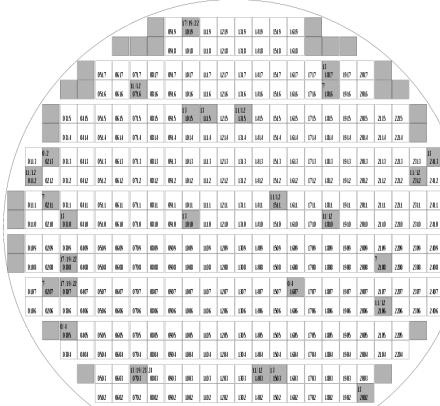


Known Good Die (KGD) maps

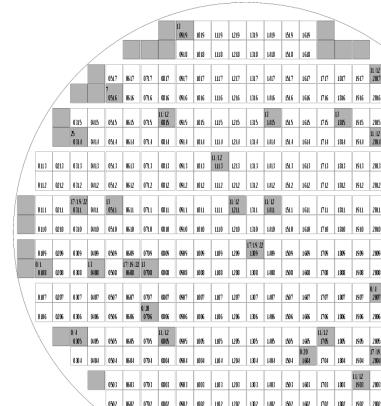
Wafer Map: K8MG5RT



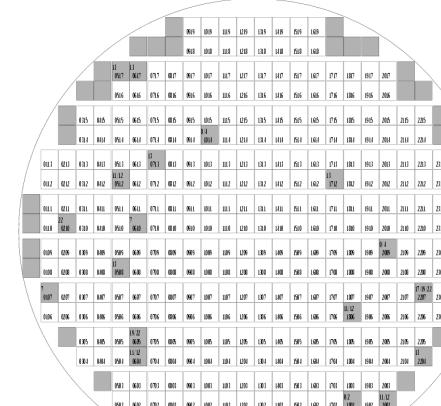
Wafer Map: X04AQYT



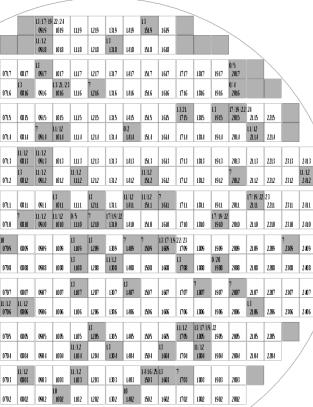
Wafer Map: X04ARFT



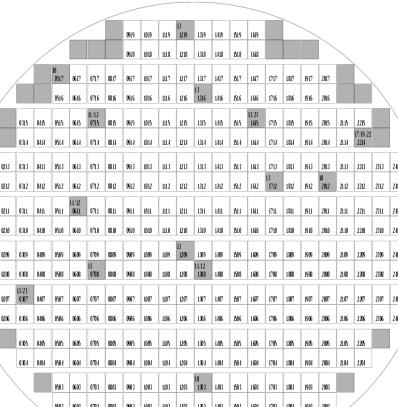
Wafer Map: X04BSWT



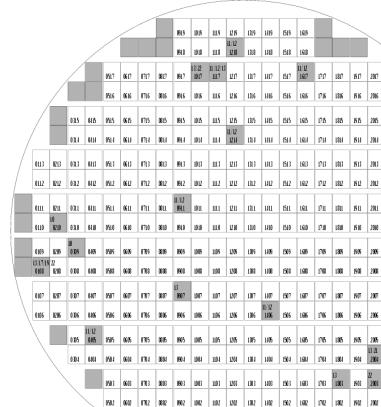
Wafer Map: X14AQXT



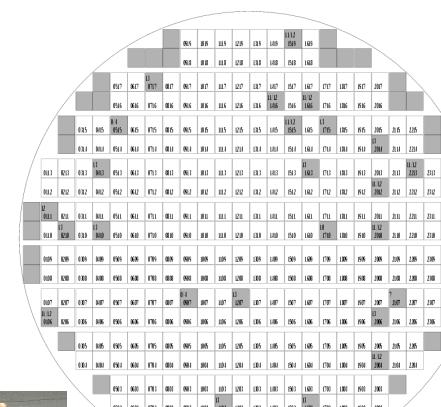
Wafer Map: X14ARET



Wafer Map: X5482PT



Wafer Map: X6482NT

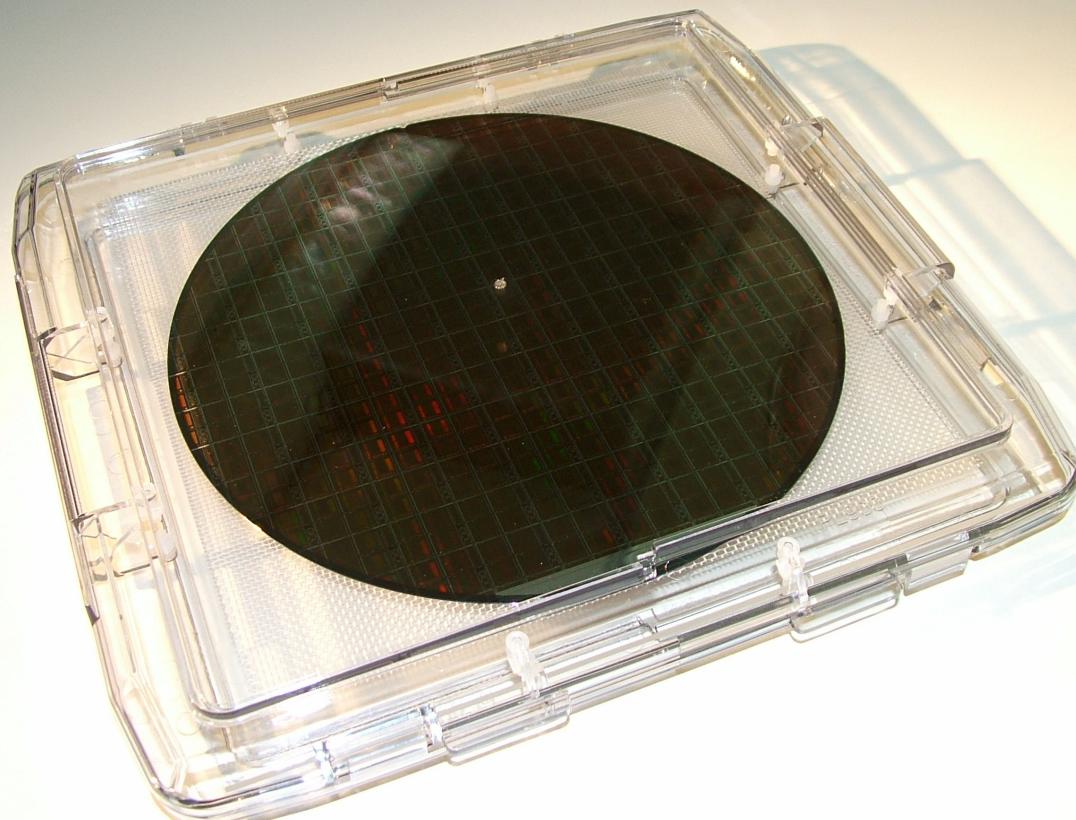


And the final tally is.....

2637



Dicing first wafer



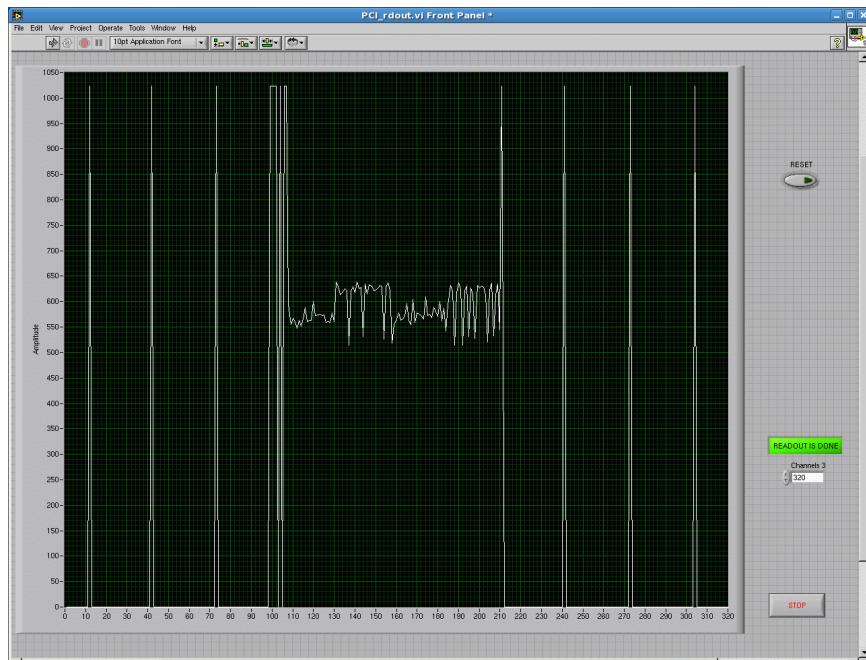
← Diced at APV
Chips stored in Gel-Paks



Test some chips



Test readout system



My glass is half-full, but.....

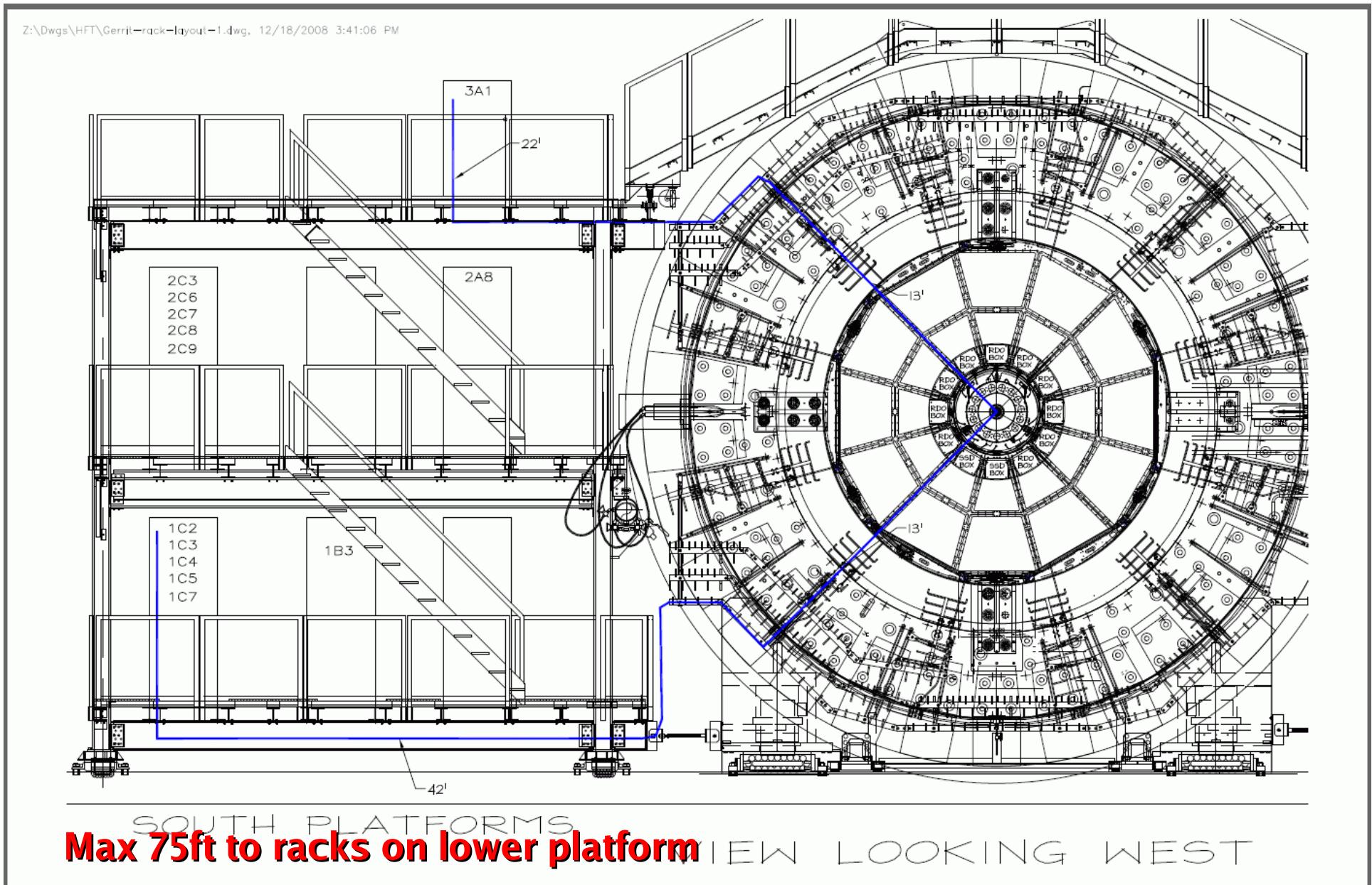
- many, many problems with readout
 - . OS incompatibilities
 - . dying I/O card and computer
 - . LabView incompatibilities
 - . I2C on APV test strip broken

Attempted solutions

- . LabView 8.6 for Linux
- . New computer
- . Use USB instead of PCI I/O card

Just started with new readout.....

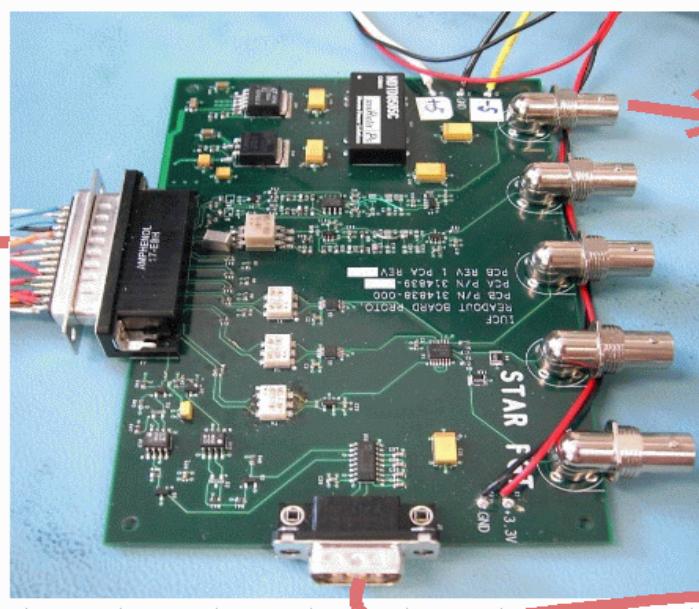
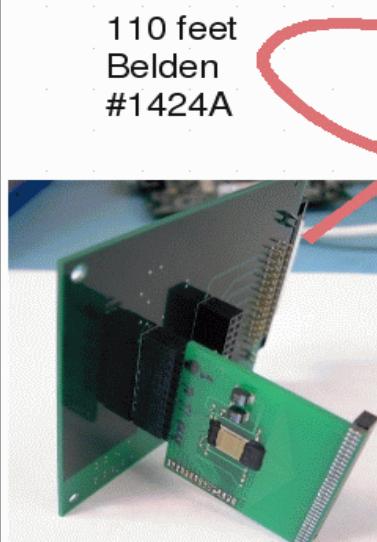
Expected cable runs



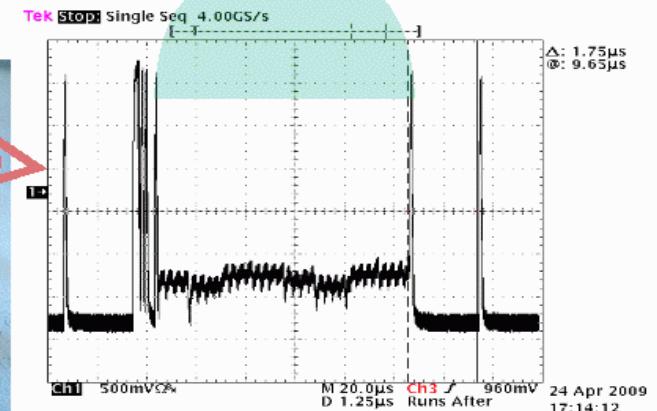
APV long cable driving test

Readout board frontend prototype and long cable test

- Demonstrated basic operation of APV
- 170% of planned cable length
- Equalization filter designed and tested
- ADC (anti-alias) filter design in progress
- Tests with Struck ADC module and full FGT APV board within next weeks



A typical APV event,
128 channels' data
(here only pedestals)



Concluding remarks

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